Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/761,154	SHEN	
Examiner	**Art Unit**	
Almis R. Jankus	2672	

SEARCHED			
Class	Subclass	Date	Examiner
345	87 96	3/15/06	3
349	77 114		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Databases: USPAT IEEE ACM	3/15/06	3
SPIE TERMS: TRANSREFLECTIVE LCD TRANSISTOR		